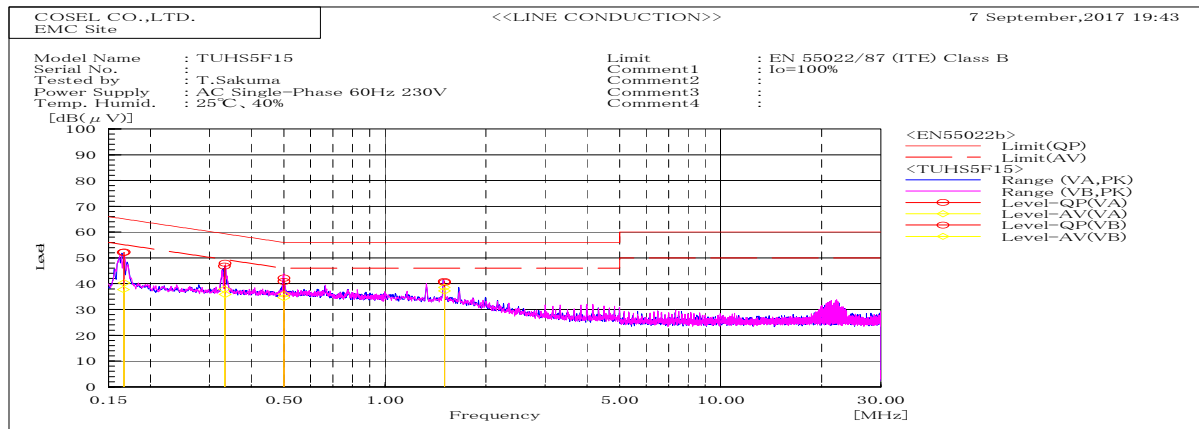
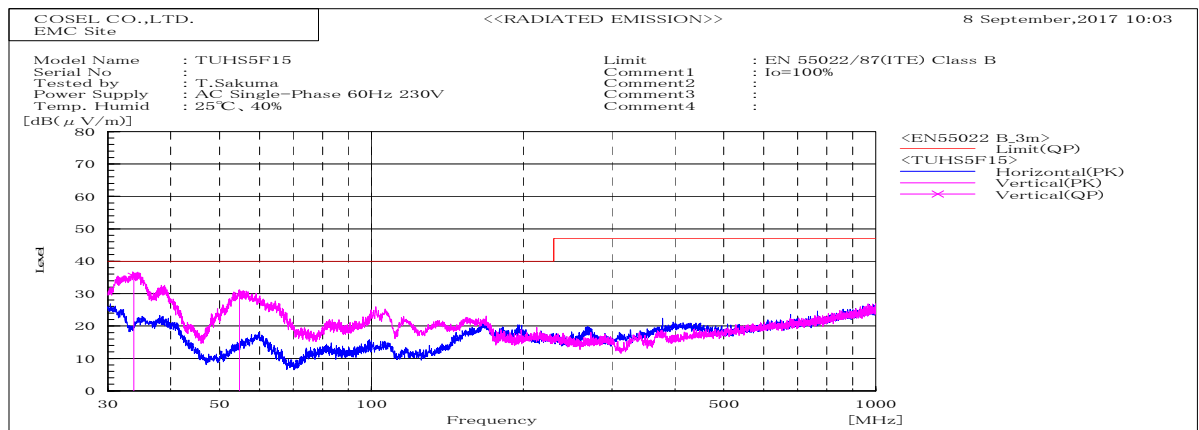


DATA SHEET		Date	12-Sep-17
Model	TUHS5F15	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sakuma



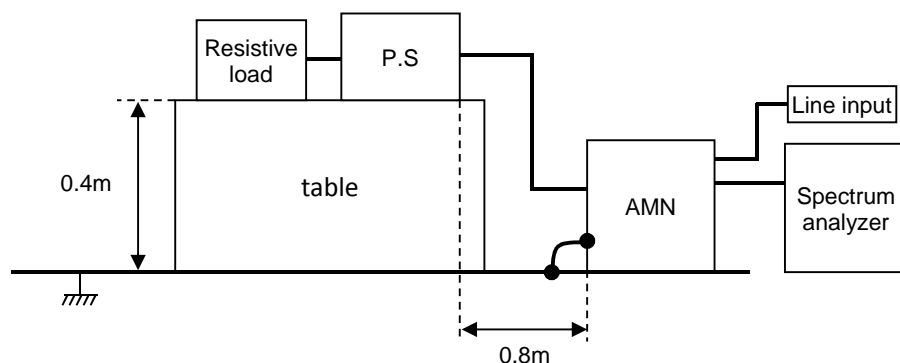
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV/m)		Limit dB(μV/m)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.16619		VB	31.2	16.8	21.0	52.2	37.8	65.1	55.1	12.9	17.3	Pass	
0.16708		VA	31.2	19.3	21.0	52.2	40.3	65.1	55.1	12.9	14.8	Pass	
0.33419		VB	27.0	15.0	20.9	47.9	35.9	59.3	49.3	11.4	13.4	Pass	
0.33235		VA	25.9	16.9	20.9	46.8	37.8	59.4	49.4	12.6	11.6	Pass	
0.4999		VA	20.0	14.9	20.9	40.9	35.8	56.0	46.0	15.1	10.2	Pass	
0.49941		VB	21.3	13.7	20.9	42.2	34.6	56.0	46.0	13.8	11.4	Pass	
1.50216		VB	19.9	17.6	21.0	40.9	38.6	56.0	46.0	15.1	7.4	Pass	
1.50454		VA	19.5	16.2	21.0	40.5	37.2	56.0	46.0	15.5	8.8	Pass	



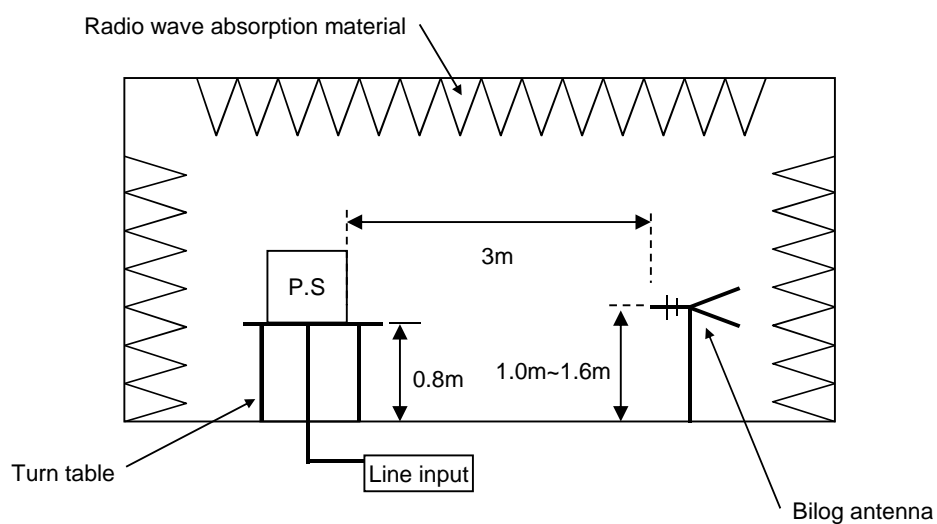
Frequency MHz	Polarization	Stability	Reading dB(μV)		Factor dB(1/m)	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
33.812	V	Stable	45.2	-9.8	-9.8	35.4	40.0	40.0	4.6	Pass	104	176	
54.752	V	Stable	50.0	-20.5	-20.5	29.5	40.0	40.0	10.5	Pass	103	359	

DATA SHEET		Date	12-Sep-17
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sakuma

1. Line conduction



2. Radiated emission



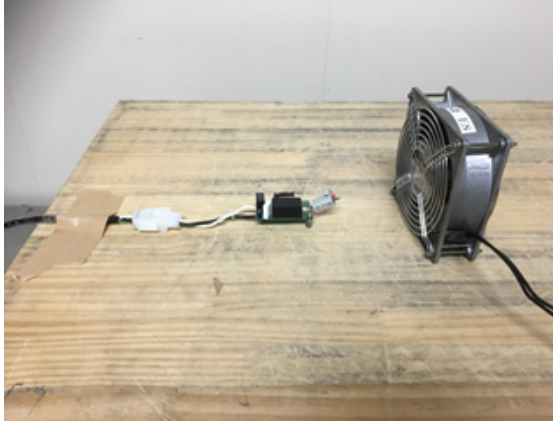
Conditions

Test: EMI

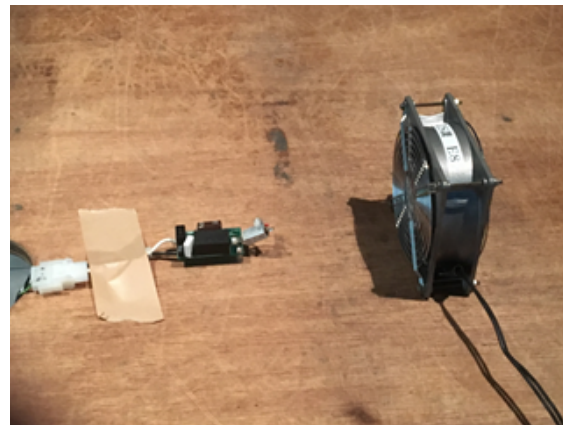
Model Name: TUHS5F15

○ Photographs of Test Set-Up

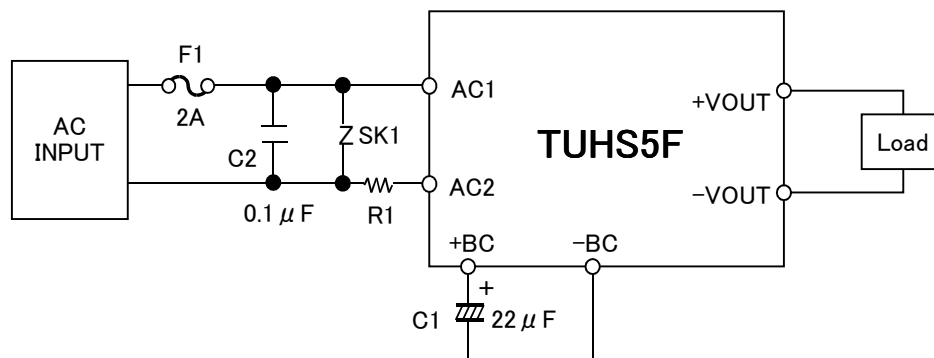
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



F1: SLT250V2A (Nippon Seisen)

R1: 1K100JA (TAMURA THERMAL DEVICE)

SK1: TND10V-511K (NIPPON CHEMI-CON)

2A

10 Ω

Fig.1 Testing circuitry